

Measurement
Techniques



Design
Verification
&
Evaluation

EVERYTHING TEST

Instrument
Selection
&
Optimization



RF TEST: RF Oscillator and VCO Measurements

Rick Daniel
Application Engineer

ROHDE & SCHWARZ

Make ideas real



Agenda



- ▶ RF Oscillator Basics
- ▶ RF Oscillator Applications
- ▶ Common RF Oscillator Measurements
 - Output Power
 - Frequency
 - Phase Noise
 - Harmonics and Spurious
- ▶ VCO-Specific Measurements
 - Tuning Sensitivity
 - Tuning Range
 - Settling time
 - Frequency Pushing and Pulling



RF Oscillator Basics



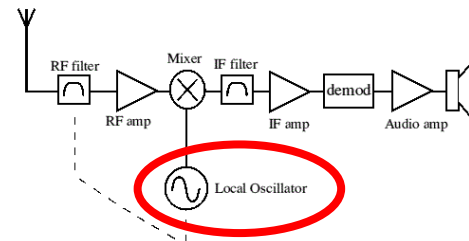
- ▶ RF Oscillators generate sinusoidal (CW) signals with output frequencies ranging from kilohertz to tens of gigahertz
- ▶ They are generally integrated into higher level assemblies, but are also sometimes used standalone
- ▶ Can be fixed frequency or tunable
- ▶ Fixed frequency oscillators may have a trim adjustment to allow small frequency changes
- ▶ Some RF Oscillator Types
 - Crystal (XO or oven-controlled, OCXO)
 - DRO (Dielectric Resonant Oscillator)
 - VCO (Voltage Controlled Oscillator)
 - MEMS (Microelectromechanical System Oscillator)
 - YIG (yttrium-iron-garnet)
 - Frequency Synthesizer



RF Oscillator Applications



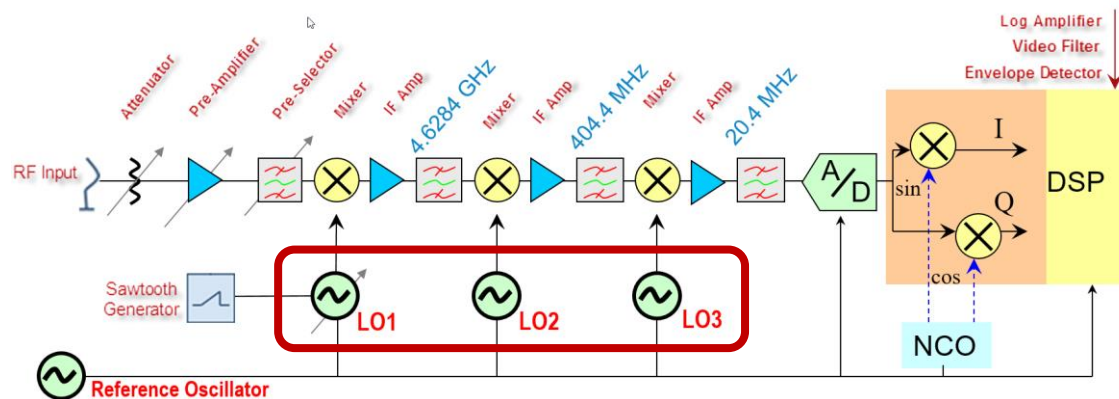
- ▶ Local Oscillators (LO) in Frequency Converters
- ▶ Clocks for Digital Systems
- ▶ Reference Oscillators for Frequency Synthesizers
- ▶ Sweeping Oscillators for Frequency Scanners
- ▶ Radar Exciters
- ▶ RF Transmitters
- ▶ RF Receivers
- ▶ Many more!



Local Oscillators (LO) in Up/Down Converters



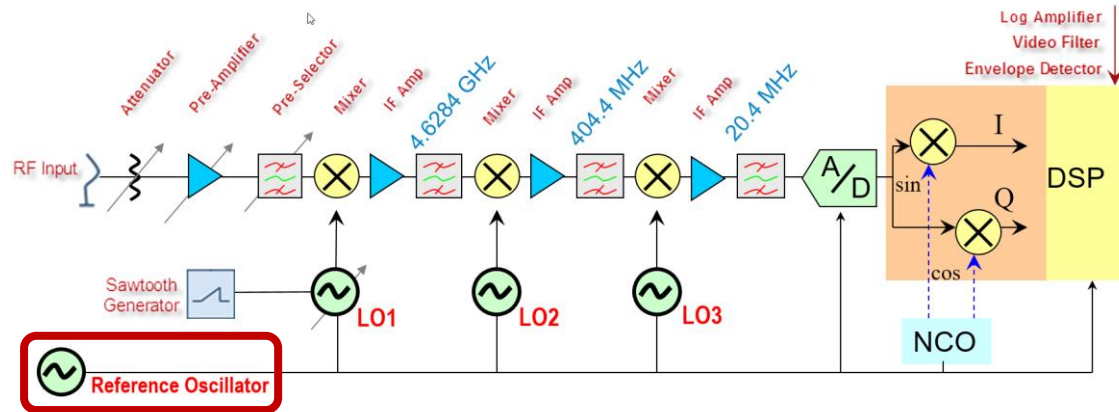
- ▶ RF oscillators are commonly used as local oscillators (LO) in up and down converters which are used in transmitters and receivers
- ▶ The diagram shows a receiver (as spectrum analyzer) block diagram with three stages of frequency conversion – each stage has an LO
- ▶ Power level and phase noise are critical parameters for an LO



Reference Oscillators



- ▶ Reference oscillators provide a very stable frequency reference used by the rest of the receiver or transmitter
- ▶ 10 MHz reference oscillators are very common, but 100 MHz or higher are also used
- ▶ All the LO's in this diagram are synthesized from the reference oscillator so the frequency accuracy and stability of entire receiver is based on the quality of the reference oscillator
- ▶ Phase noise and stability are critical parameters for a reference oscillator



RF Oscillator Measurements



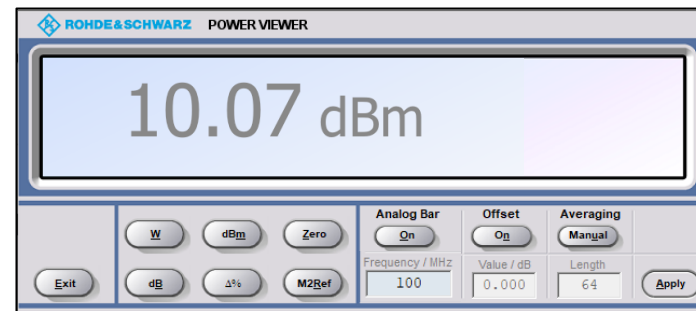
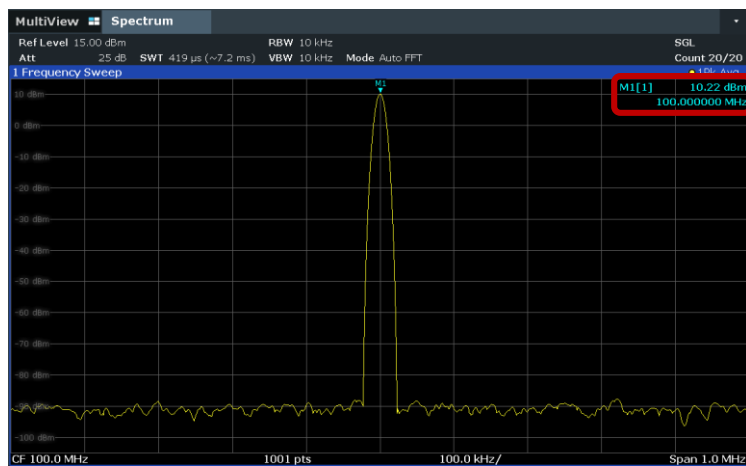
- ▶ Common oscillator RF measurements
 - Output Power (over frequency, if tunable)
 - Frequency Accuracy
 - Phase Noise
 - Harmonics
 - Spurious

- ▶ Additional measurements for VCOs (Voltage Controlled Oscillators)
 - Tuning Sensitivity (Hz/V)
 - Tuning Range
 - Settling Time
 - Frequency Pushing and Pulling

RF Output Power



- ▶ This is a relatively simple measurement that is measured over the frequency range of the oscillator
- ▶ The output level is measured using a spectrum analyzer or a power meter
- ▶ These are measurements of a 100 MHz OCXO



Frequency Error



- ▶ RF frequency used to be measured using a dedicated instrument called a frequency counter
- ▶ Frequency counters have been almost entirely replaced with the frequency counter function on modern spectrum analyzers
- ▶ Important Points
 - The frequency accuracy of a spectrum analyzer is only as good as its reference, so an external GPS, cesium, or rubidium based reference should be used
 - the standard marker accuracy isn't sufficient – the counter function must be used
- ▶ The screenshot shows the frequency of a 10 MHz OCXO to be 10.000000350 MHz → error = 0.35 Hz
- ▶ This is expressed in parts per million (ppm) or as a simple ratio in scientific notation
 - $0.35 / 10e6 \times 1e6 = 0.035$ ppm
 - $0.35 / 10e6 = 3.5 \times 10^{-8}$



Phase Noise



- ▶ Output level and frequency are fairly straightforward concepts and are relatively easy to measure
- ▶ Phase noise is more complex, both in concept and in measurement, so we'll spend a little time reviewing the concept of phase noise
- ▶ Ideally, the output of an oscillator would be a perfect sine wave, but this is never possible in the real world
- ▶ Along with spurious and harmonics, phase noise is a very important measurement of how close an oscillator's output is to the ideal sine wave



What is Phase Noise?



- **Ideal Signal (noiseless)**

$$V(t) = A \sin(2\pi vt)$$

where

A = amplitude

v = frequency

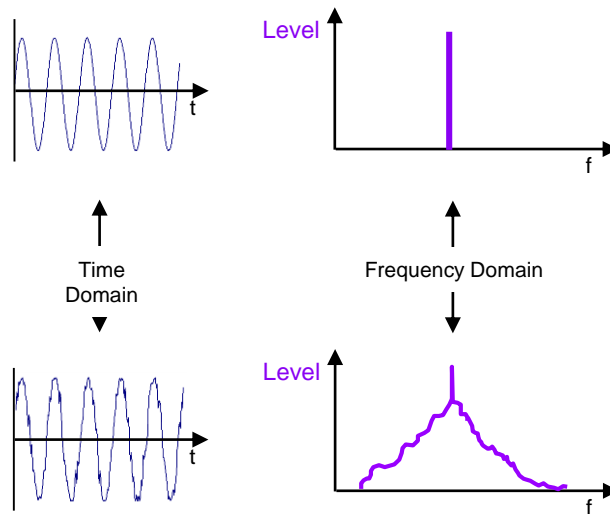
- **Real Signal**

$$V(t) = [A + E(t)] \sin(2\pi vt + \phi(t))$$

where

$E(t)$ = amplitude fluctuations

$\phi(t)$ = phase fluctuations

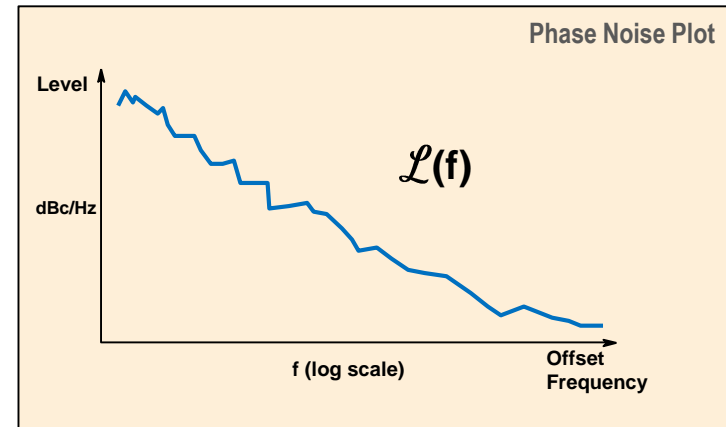
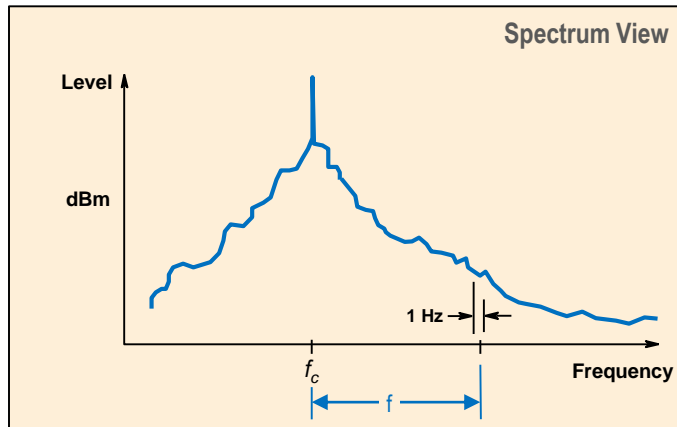


- Phase Noise is unintentional phase modulation that spreads the signal spectrum in the frequency domain
- Phase Noise is equivalent to jitter in the time domain

Phase Noise Concept



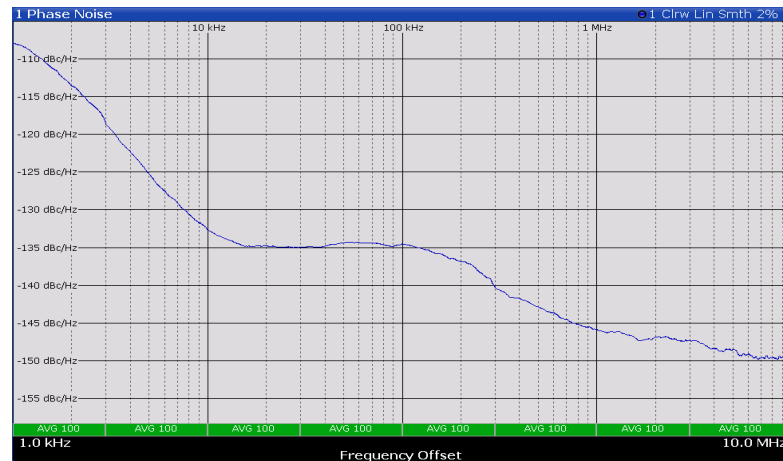
- ▶ Phase noise can be thought of as the level of noise in a 1 Hz bandwidth at some offset from the signal frequency, relative to the total signal power (see left graphic)
- ▶ $\mathcal{L}(f)$ has units of dBc/Hz ($\mathcal{L}(f)$ is pronounced “script L of F”)
- ▶ A standard phase noise plot displays this with the level (dBc/Hz) on the y-axis and the offset frequency on the x-axis (see right graphic)
- ▶ The offset frequency is on a log scale



Phase Noise Concept



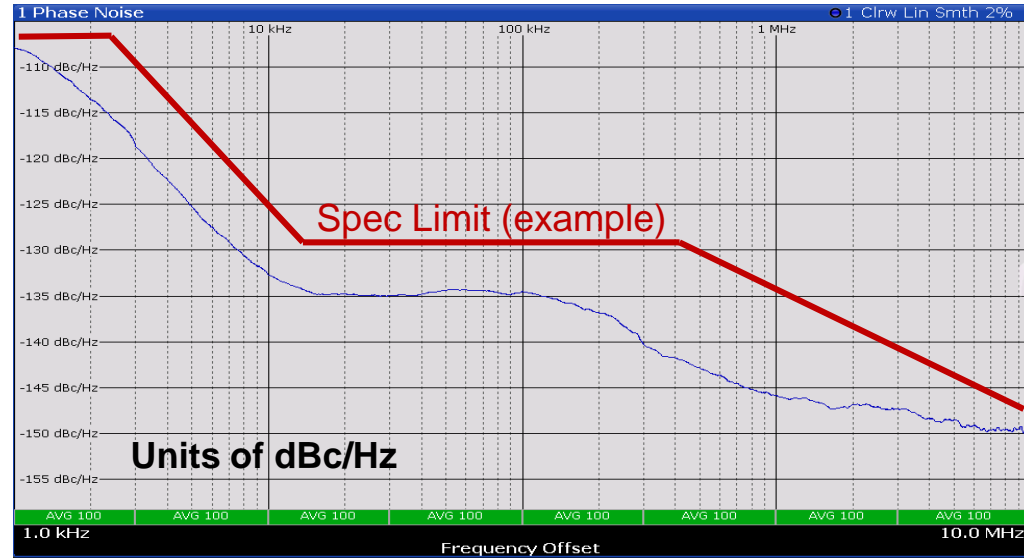
- Phase noise requirements can be expressed in several different ways
 - The phase noise curve must be below some specified maximum curve
 - Specific points on the curve must be below specified values (spot noise)
 - Integrated phase noise (over a certain range of offset frequencies) must be below a specified value, which can be expressed in units of :
 - dBc (integrated phase noise)
 - Hz (residual FM)
 - Degrees or radians (residual PM)
 - Seconds (jitter)



Quantifying Phase Noise: $\mathcal{L}(f)$



- Plot



- Spot Noise

2 Spot Noise		
Type	Offset Frequency [T1]	Phase Noise [T1]
Fixed	1.00 kHz	-107.89 dBc/Hz
Fixed	10.00 kHz	-132.72 dBc/Hz
Fixed	100.00 kHz	-134.53 dBc/Hz
Fixed	1.00 MHz	-145.83 dBc/Hz
Fixed	10.00 MHz	-149.60 dBc/Hz



Spot Noise offsets are user-definable
(default to decade offsets)

Integrated Phase Noise



► Values calculated from integration of the phase noise curve

– Integrated Phase Noise

$$\int \mathcal{L}(f) df$$

(dBc)

– Residual PM

$$\frac{180^\circ}{\pi} \sqrt{2 \int \mathcal{L}(f) df}$$

(deg or rad)

– Residual FM

$$\sqrt{2 \int f^2 \mathcal{L}(f) df}$$

(Hz)

– Jitter

$$\frac{1}{2\pi f_c} \sqrt{2 \int \mathcal{L}(f) df}$$

(sec)

2 Integrated Measurements

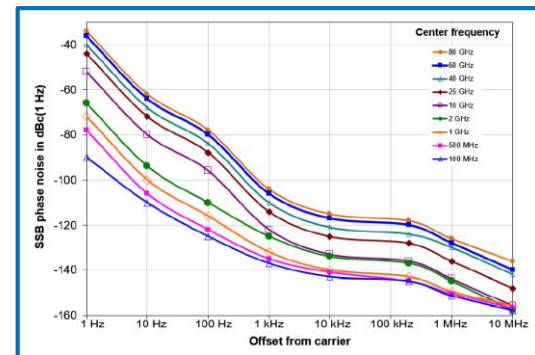
Range	Trace	Start Offset	Stop Offset	Weighting	Int Noise	PM	FM	Jitter
1	1	1.000 Hz	1.000 MHz		-71.73 dBc	0.02 °/366.60 µrad	950 mHz	583.460 fs



Measuring Phase Noise



- ▶ Phase noise can be measured with a Spectrum Analyzer or with a dedicated Phase Noise analyzer (also called a Signal Source Analyzer)
- ▶ Spectrum analyzers are convenient and fast, but have limited sensitivity due to their own internal phase noise, and their minimum offset frequency is limited to 1 Hz
- ▶ To determine if a spectrum analyzer is adequate for a particular phase noise measurement, check the spectrum analyzer data sheet for the internal phase noise
- ▶ The SA's phase noise should be 10 dB or more below the level we want to measure
- ▶ If spectrum analyzer is not adequate for the measurement, we must use a dedicated phase noise analyzer which can measure 30-40 dB lower phase noise than even the best spectrum analyzer
- ▶ Phase noise analyzers use very different hardware and measurement techniques than spectrum analyzers



R&S FSW Spectrum Analyzer
Phase Noise (from Data Sheet)

Phase Noise Measurement Instruments



- ▶ Until the early 2000s, a phase noise analyzer was a rack of equipment controlled by a computer and required a two-day training class
- ▶ Modern phase noise analyzers are single box instruments that look very similar to a spectrum analyzer and can be learned in just a few minutes
- ▶ Some phase noise analyzers can also function as spectrum analyzers



HP3048 Phase Noise System



FSW Spectrum Analyzer

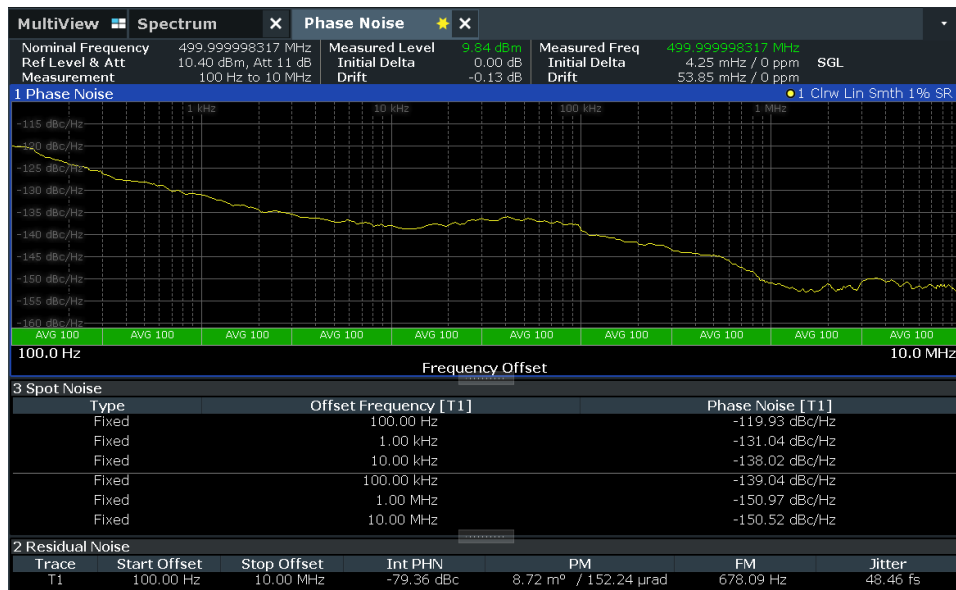


FSWP Signal Source Analyzer

Phase Noise Measurement



- This screenshot shows a phase noise measurement of a 500 MHz source over an offset range of 100 Hz to 10 MHz



← Phase Noise curve

← Spot Noise values at each offset decade (offset frequencies are user settable)

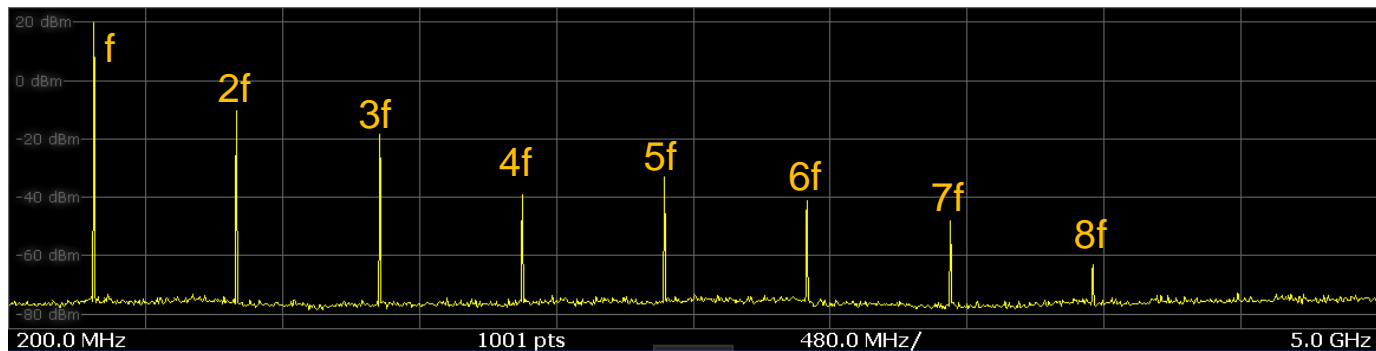
← Integrated Phase Noise (dBc), Residual PM (deg/rad), Residual FM (Hz), and Jitter (s)



Harmonics



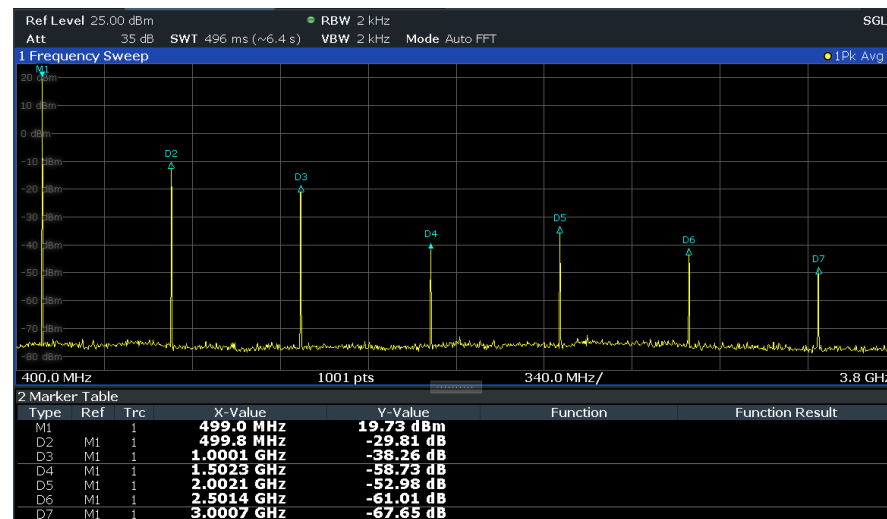
- ▶ Harmonics are another measurement of oscillator signal purity
- ▶ For a signal at frequency f , harmonic distortion energy falls at $2f$, $3f$, $4f$, ...
- ▶ Sub-harmonics ($f/2$ or other fractional ratios) are sometimes present on the output
- ▶ Harmonics generally present less of a problem in a design than phase noise, but in some systems the harmonic content must be minimized
- ▶ Harmonic levels are expressed as dB relative to the fundamental/carrier, or dBc



Harmonic Measurement



- ▶ Harmonics are measured using a spectrum analyzer
- ▶ The traditional test method is to set the spectrum analyzer for a wide sweep that covers the frequency range from the fundamental to the highest harmonic of interest, then use markers and delta markers to measure the various harmonic levels
- ▶ The resolution bandwidth must be set low enough that the noise floor is well below the measured harmonics, which slows the sweep
- ▶ This technique works, but the analyzer spends time sweeping between the harmonics (this measurement took ~6.4 seconds)
- ▶ There is a faster, more efficient method that provides more information



Reference Marker →

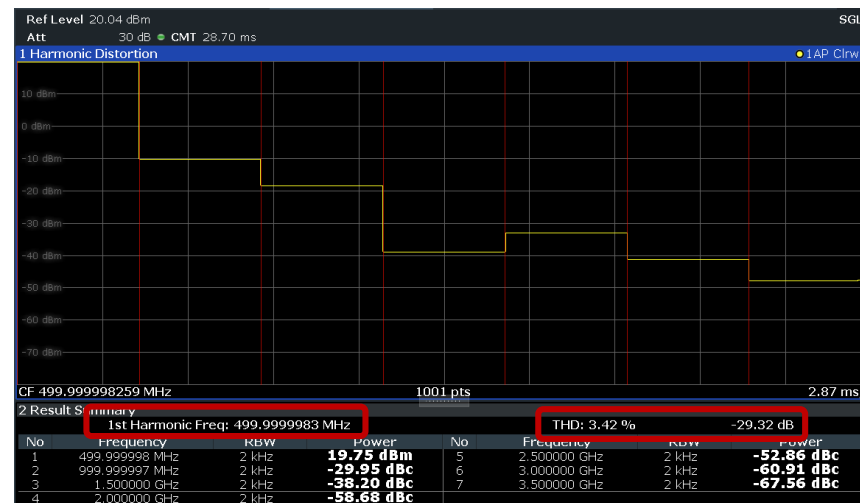
Delta Markers →



Harmonic Measurement



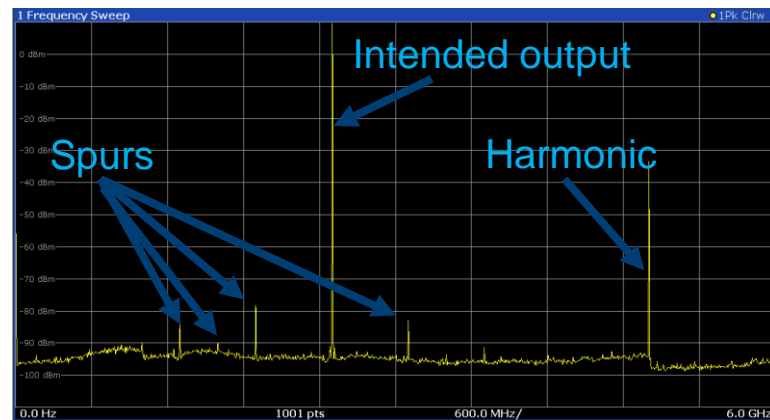
- ▶ Some spectrum analyzers have a harmonic measurement utility
- ▶ This utility finds and measures the fundamental frequency very accurately and calculates the harmonic frequencies
- ▶ Then the analyzer internally measures only at those frequencies without wasting sweep time between the harmonics
- ▶ This technique has advantages:
 - Much faster (29 ms vs. 6.4 s in this example)
 - Measures fundamental frequency with 0.1 Hz accuracy
 - Calculates total harmonic distortion (THD) in units of % and dB



Spurious



- ▶ Spurious emissions, or spurs (also called non-harmonic outputs), are unwanted discrete tones produced by the oscillator that are not harmonically related to the output frequency
- ▶ Spurious output levels are usually specified lower than harmonic levels (-70 to -100 dBc)
- ▶ Spurs are more common in frequency synthesizers than in simple oscillator components like crystals or VCOs
- ▶ Common sources of spurs are mixer distortion products, switching power supply clock leakage, leakage from other clocks within a device, etc.
- ▶ Spurs are measured using a spectrum analyzer



Spurious



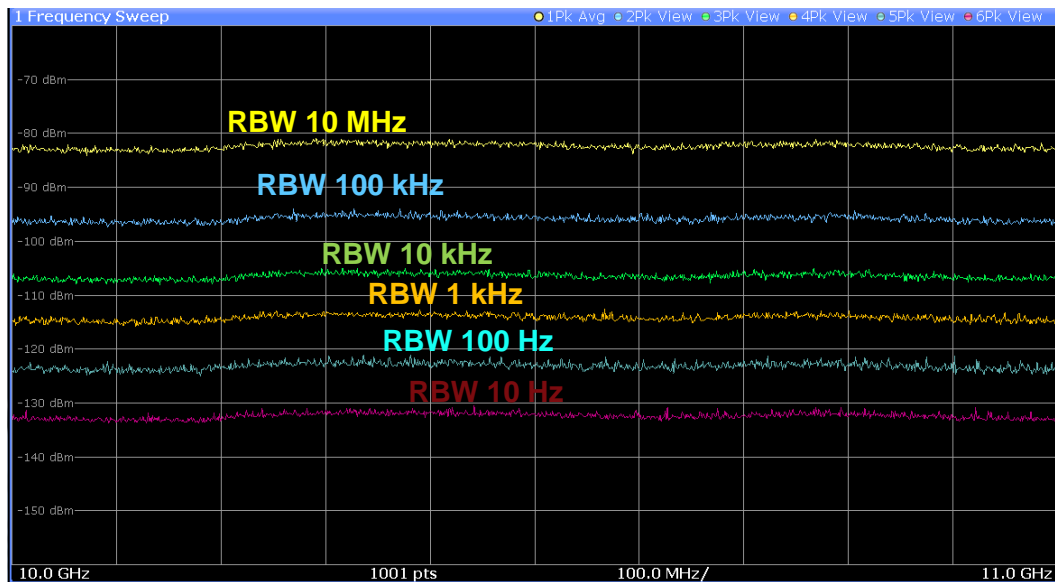
- ▶ Harmonics are easy to measure because we know exactly where to look
- ▶ Spurs are low-level and occur at unknown frequencies so we must search over a wide frequency range (can be many GHz) to look for them
- ▶ Spur searching can be a very time-consuming process
 - Spectrum analyzer must sweep over large span
 - Low resolution bandwidth (RBW) necessary to reduce SA noise floor below spur level, which results in slow sweep
 - Many sweep points must be used to accurately measure spur frequency
 - Spurs must be tested to see if they are real or internal to SA



RBW, Noise Floor, and Sweep Time



- ▶ We want the SA noise floor to be at least 10 dB below the spurious spec level
- ▶ Low noise floor requires low RBW, which results in much longer sweep time
- ▶ A low level spur search over a wide frequency range can take hours
- ▶ Noise floor varies with frequency – use segmented sweep for optimized RBW



.06 s/GHz

1.2 s/GHz

25 s/GHz

276 s/GHz

456 s/GHz

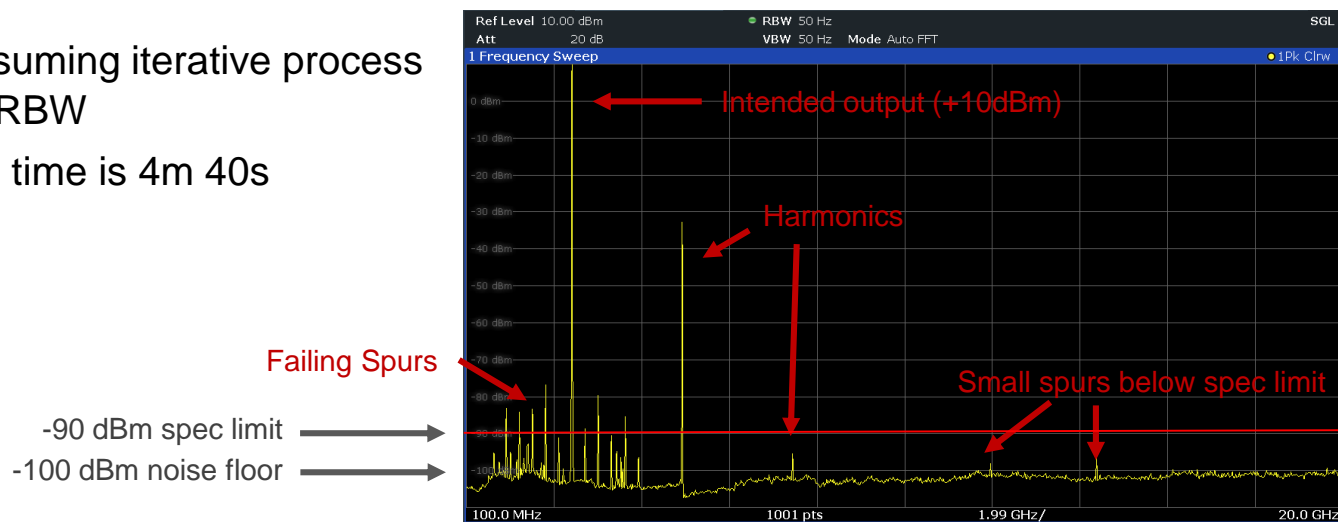
2428 s/GHz (>40 minutes/GHz)



Spurious Measurement



- ▶ Example spurious spec:
Output at 2.5 GHz, +10 dBm, non-harmonic spurs must be < -90 dBm from 100 MHz – 20 GHz
- ▶ Since we're searching for -90 dBm spurs, our noise floor should be < -100 dBm
- ▶ We have to set the input attenuator to 20 dB to accommodate the +10 dBm intentional signal which raises the noise floor, so we have to use a low 50 Hz RBW filter to get the required noise floor
- ▶ It can be a time consuming iterative process to find the optimum RBW
- ▶ The resulting sweep time is 4m 40s



Fast Spurious Measurement



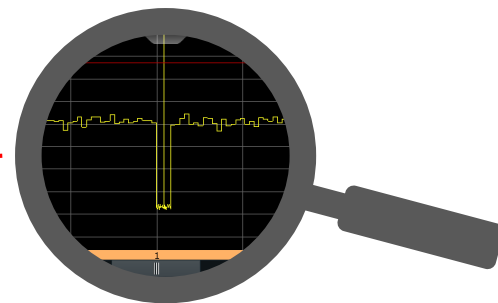
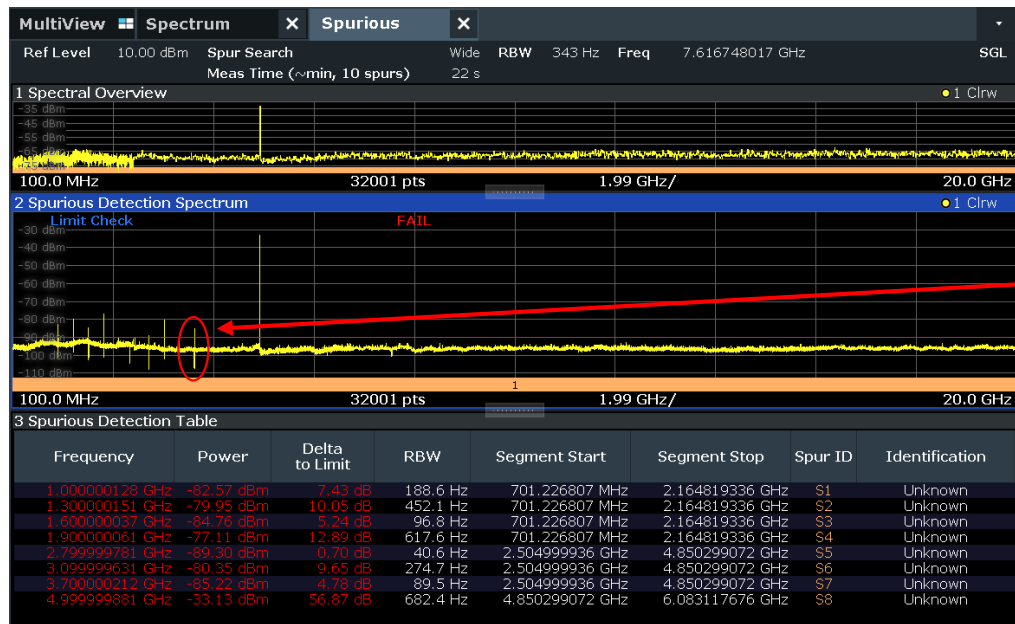
- ▶ There is a more modern way to do spur searching that uses a three step process using FFT technology
 - Step 1: SA does a fast sweep to estimate its noise floor. Since the noise floor varies over frequency, the analyzer divides the sweep into segments, each with its own optimum RBW setting
 - Step 2: SA does a sweep with a minimal 2-3 dB noise floor margin and generates a list of candidate spurs (many of these could be SA spurs or false spurs due to the high noise floor)
 - Step 3: SA measures each candidate spur in a small bandwidth with a much smaller RBW (more noise floor margin) to determine if it is a real spur (not an SA spur) and to accurately measure its frequency and level
- ▶ This approach saves setup time (no trial and error to manually determine optimum RBW)
- ▶ Measurement time is also faster – the lower the required spur measurement level, the bigger the speed advantage – up to 40x faster



Fast Spurious Measurement



- ▶ This is the same measurement as before using the fast spur search technique
- ▶ This measurement was easier to setup and took about 46 seconds (vs 4m 40s)



VCO Measurements



- ▶ The measurements discussed to this point apply to all RF oscillator types
- ▶ Voltage Controlled Oscillators (VCO's) and other tunable oscillators have some additional parameters that may need to be tested
 - Tuning range
 - Tuning sensitivity
 - Settling time
 - Frequency pushing (output frequency change vs supply voltage)
 - Frequency pulling (output frequency change vs load impedance)



VCO-0964



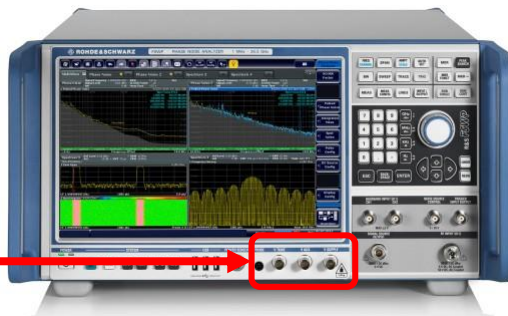
MC1648 VCO

VCO Measurements



- ▶ VCO testing requires a spectrum analyzer, phase noise analyzer, and up to three controllable power supplies for tuning range and sensitivity measurements
- ▶ In the past, this required separate instruments and controlling software, but modern Signal Source Analyzers integrate all these functions into a single instrument
- ▶ SSA's have many built-in functions geared specifically for VCO testing
 - Two V_{supply} outputs for frequency pushing measurements
 - A low-noise V_{tune} output for tuning range and sensitivity
 - A spectrum analyzer for output power, spurious, and harmonic testing
 - A phase noise analyzer for low-level phase noise and for tracking drifting sources

Controllable V_{supply} and
 V_{tune} outputs

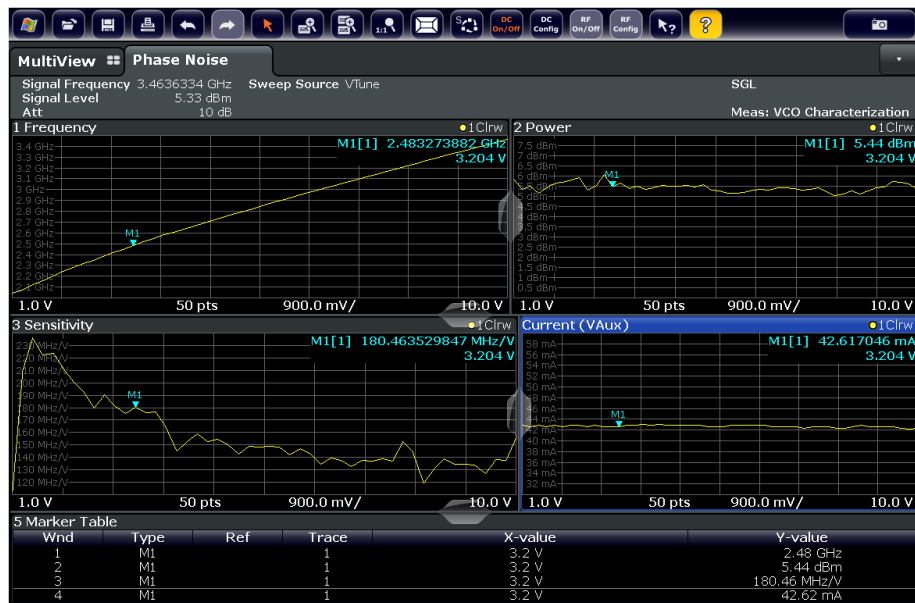


R&S FSWP Phase Noise Analyzer
and VCO Tester

VCO Performance vs Tuning Voltage



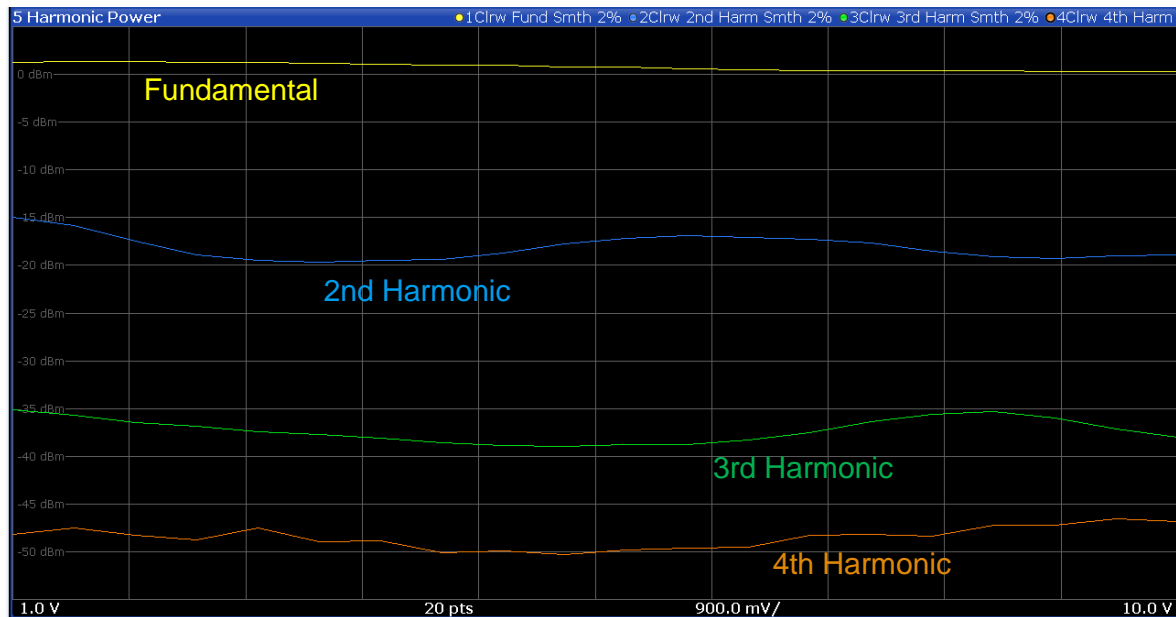
- ▶ This screenshot shows four measurements, all as a function of Tuning Voltage (V_{tune})
 - Output Frequency, Output Power, Tuning Sensitivity, and Supply Current
- ▶ The analyzer measures these four quantities as it sweeps the tuning voltage from 1 to 10 V



Harmonic Levels vs Tuning Voltage



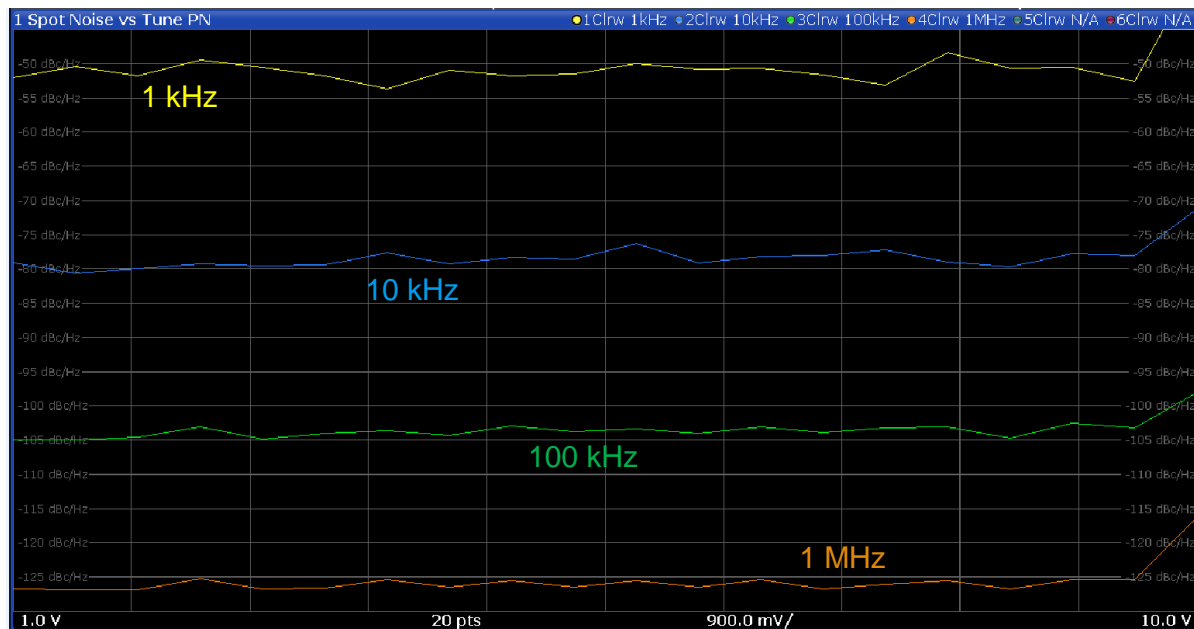
- Measurement of the fundamental, 2nd, 3rd, and 4th harmonic output levels vs tuning voltage



Phase Noise vs Tuning Voltage



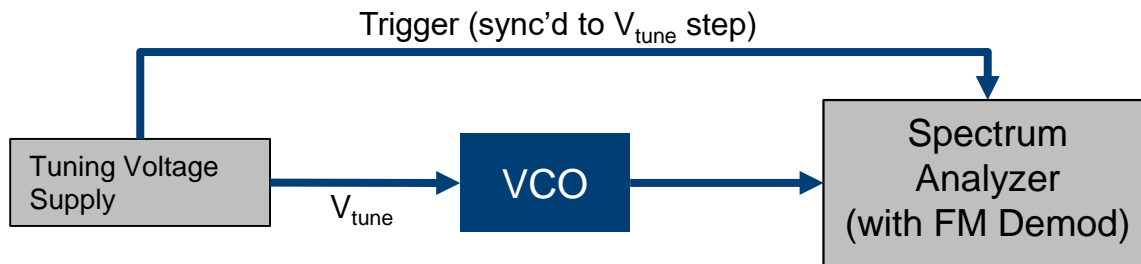
- Measurement of phase noise (spot noise at four offsets) vs tuning voltage



Settling Time



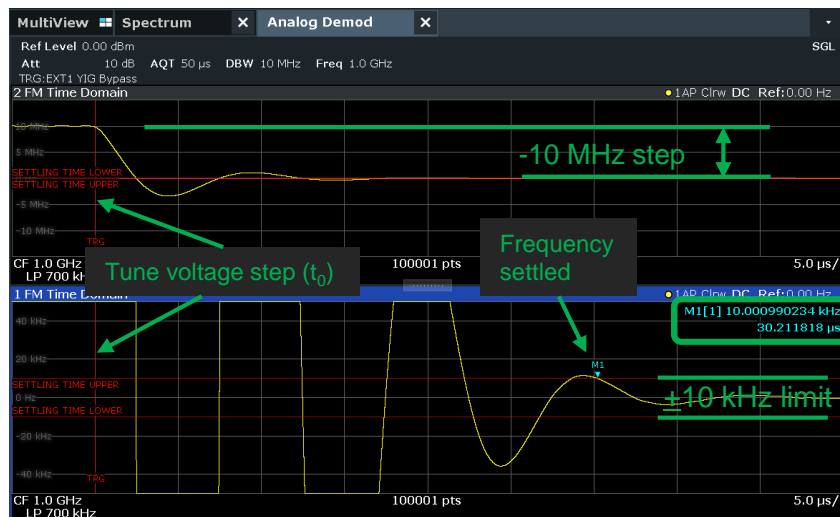
- ▶ VCOs are tunable, so the tuning speed, or settling time, is often specified
- ▶ The settling time is typically defined as the time between a step change in tuning voltage (t_0) and the point when the output frequency is within some tolerance of the final frequency
- ▶ Settling time is measured using a spectrum analyzer with an FM demodulation function to measure the instantaneous output frequency of the VCO



Settling Time Measurement



- ▶ V_{tune} is stepped down to change the VCO output frequency (-10 MHz in this example)
- ▶ The step in V_{tune} establishes t_0 and triggers the 'Frequency vs Time' measurement
- ▶ The measurement is shown in two different scales to illustrate the overall step (top) and zoomed in (bottom) to view the final settling to within 10 kHz
- ▶ The measured settling time is 30.21 μs (10 MHz step settles within ± 10 kHz in 30.21 μs)



Scale: 5 MHz/div

Scale: 20 kHz/div

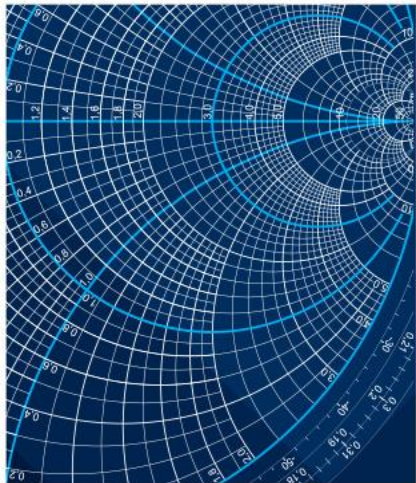


SUMMARY / Q&A



- ▶ RF oscillators are used to create high-frequency sinusoidal signals and are used in a wide variety of RF equipment
- ▶ Several types of RF oscillators are available, from fixed frequency crystal oscillators to tunable voltage controlled oscillators
- ▶ Characterizing RF oscillators, especially tunable devices, requires a lot of testing over a wide range of input conditions
- ▶ Modern test equipment makes performing these measurements far easier than it was even a few years ago





Measurement
Techniques



Design
Verification
&
Evaluation

EVERYTHING TEST

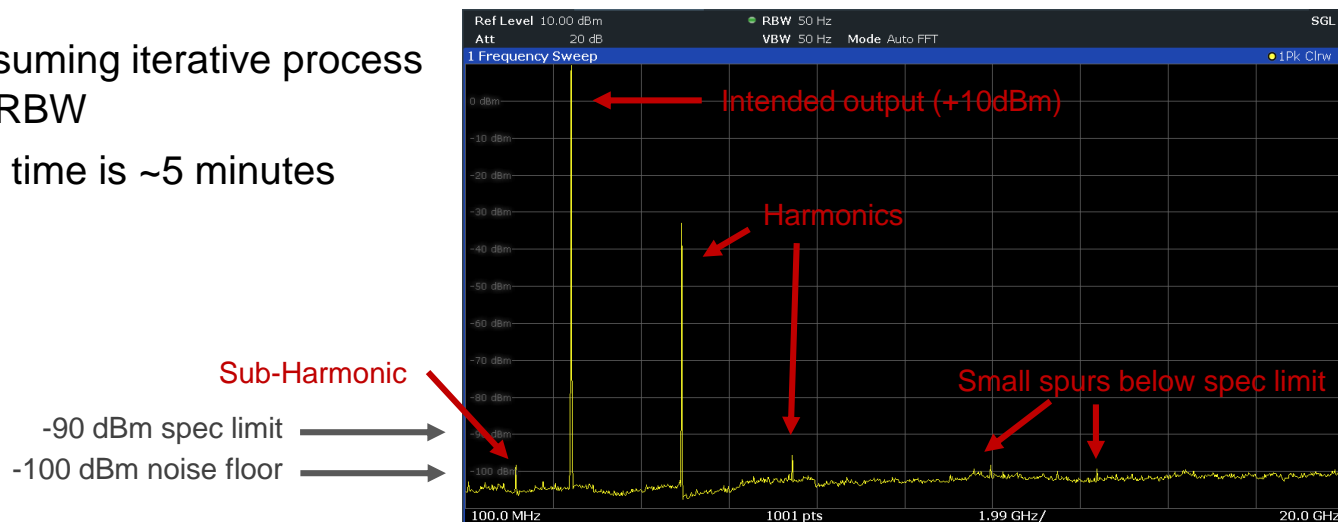
Instrument
Selection
&
Optimization



Spurious Measurement



- ▶ Example spurious spec:
Output at 2.5 GHz, +10 dBm, non-harmonic spurs must be < -90 dBm from 100 MHz – 20 GHz
- ▶ Since we're searching for -90 dBm spurs, our noise floor should be < -100 dBm
- ▶ We have to set the input attenuator to 20 dB to accommodate the +10 dBm intentional signal which raises the noise floor, so we have to use a low 50 Hz RBW filter to get the required noise floor
- ▶ It can be a time consuming iterative process to find the optimum RBW
- ▶ The resulting sweep time is ~5 minutes



Fast Spurious Measurement



- ▶ This is the same measurement as before using the fast spur search technique
- ▶ The only spur found is actually the second harmonic
- ▶ This measurement was easier to setup and took about 43 seconds (vs 5 minutes)

